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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	2400
Number of Logic Elements/Cells	10800
Total RAM Bits	573440
Number of I/O	404
Number of Gates	129600
Voltage - Supply	1.71V ~ 1.89V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	560-LBGA Exposed Pad, Metal
Supplier Device Package	560-MBGA (42.5x42.5)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv405e-7bg560c

Configuration through the TAP uses the CFG_IN instruction. This instruction allows data input on TDI to be converted into data packets for the internal configuration bus.

The following steps are required to configure the FPGA through the boundary-scan port (when using TCK as a start-up clock).

1. Load the CFG_IN instruction into the boundary-scan instruction register (IR)
2. Enter the Shift-DR (SDR) state
3. Shift a configuration bitstream into TDI
4. Return to Run-Test-Idle (RTI)
5. Load the JSTART instruction into IR
6. Enter the SDR state
7. Clock TCK through the startup sequence
8. Return to RTI

Configuration and readback via the TAP is always available. The boundary-scan mode is selected by a <101> or <001> on the mode pins (M2, M1, M0). For details on TAP characteristics, refer to XAPP139.

Configuration Sequence

The configuration of Virtex-E devices is a three-phase process. First, the configuration memory is cleared. Next, configuration data is loaded into the memory, and finally, the logic is activated by a start-up process.

Configuration is automatically initiated on power-up unless it is delayed by the user, as described below. The configuration process can also be initiated by asserting $\overline{\text{PROGRAM}}$. The end of the memory-clearing phase is signalled by $\overline{\text{INIT}}$ going High, and the completion of the entire process is signalled by DONE going High.

The power-up timing of configuration signals is shown in Figure 20.

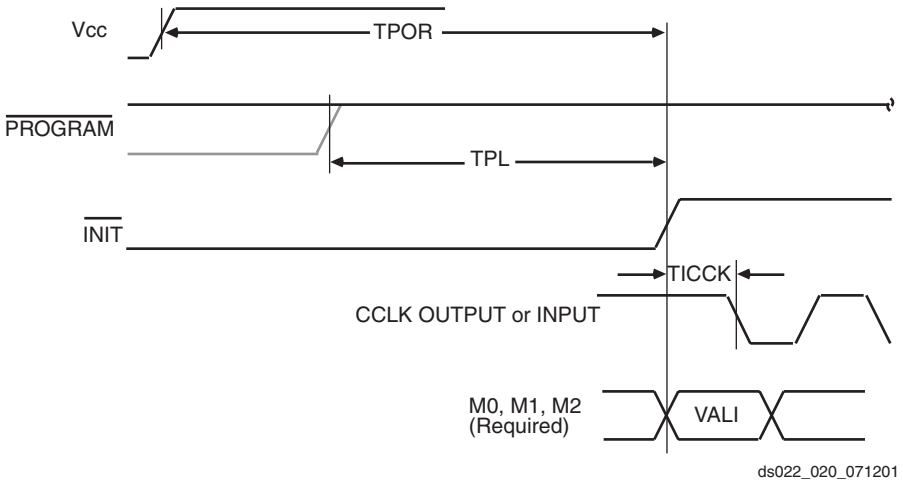

Figure 20: **Power-Up Timing Configuration Signals**

The corresponding timing characteristics are listed in Table 12.

Table 12: **Power-up Timing Characteristics**

Description	Symbol	Value	Units
Power-on Reset[1]	T_{POR}	2.0	ms, max
Program Latency	T_{PL}	100.0	µs, max
CCLK (output) Delay	T_{ICCK}	0.5	µs, min
		4.0	µs, max
Program Pulse Width	$T_{PROGRAM}$	300	ns, min

Notes:
1. T_{POR} delay is the initialization time required after V_{CCINT} reaches the recommended operating voltage.

Delaying Configuration

$\overline{\text{INIT}}$ can be held Low using an open-drain driver. An open-drain is required since $\overline{\text{INIT}}$ is a bidirectional open-drain pin that is held Low by the FPGA while the configuration memory is being cleared. Extending the time that the pin is Low causes the configuration sequencer to wait. Thus, configuration is delayed by preventing entry into the phase where data is loaded.

Start-Up Sequence

The default Start-up sequence is that one CCLK cycle after DONE goes High, the global 3-state signal (GTS) is released. This permits device outputs to turn on as necessary.

One CCLK cycle later, the Global Set/Reset (GSR) and Global Write Enable (GWE) signals are released. This permits

the internal storage elements to begin changing state in response to the logic and the user clock.

The relative timing of these events can be changed. In addition, the GTS, GSR, and GWE events can be made dependent on the DONE pins of multiple devices all going High, forcing the devices to start synchronously. The sequence can also be paused at any stage until lock has been achieved on any or all DLLs.

Readback

The configuration data stored in the Virtex-E configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUT RAMs, and block RAMs. This capability is used for real-time debugging. For more detailed information, see application note XAPP138 “Virtex FPGA Series Configuration and Readback”.

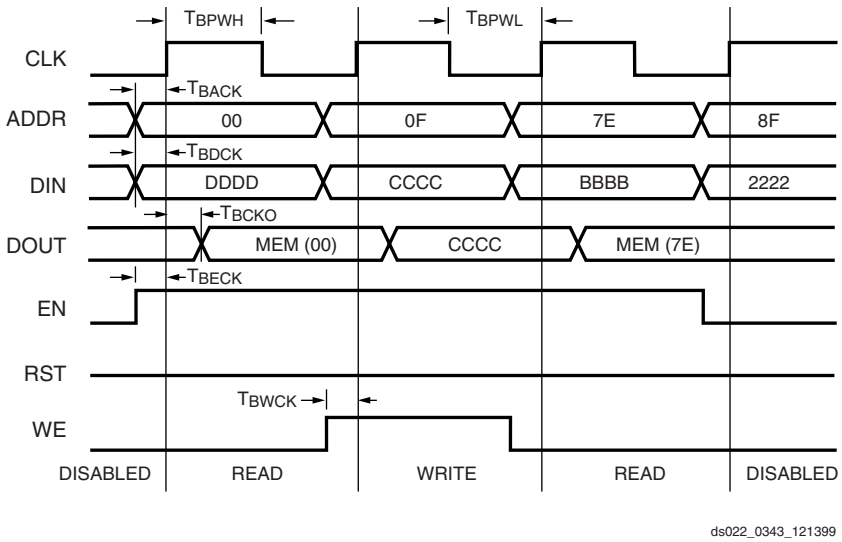

Figure 33: **Timing Diagram for Single Port Block SelectRAM+ Memory**

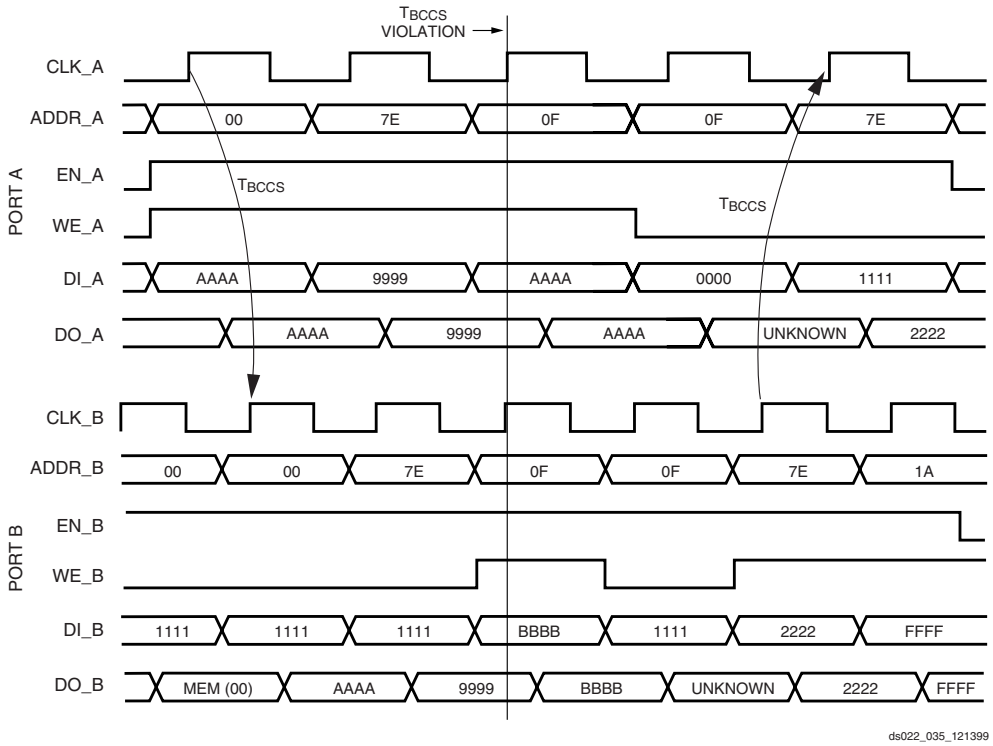

Figure 34: **Timing Diagram for a True Dual-port Read/Write Block SelectRAM+ Memory**

At the third rising edge of CLKA, the T_{BCCS} parameter is violated with two writes to memory location 0x0F. The DOA and DOB busses reflect the contents of the DIA and DIB busses, but the stored value at 0x0F is invalid.

At the fourth rising edge of CLKA, a read operation is performed at memory location 0x0F and invalid data is present on the DOA bus. Port B also executes a read operation to memory location 0x0F and also reads invalid data.

At the fifth rising edge of CLKA a read operation is performed that does not violate the T_{BCCS} parameter to the previous write of 0x7E by Port B. THe DOA bus reflects the recently written value by Port B.

standard requires a Differential Amplifier input buffer and a Push-Pull output buffer.

SSTL3 — Stub Series Terminated Logic for 3.3V

The Stub Series Terminated Logic for 3.3 V, or SSTL3 standard is a general purpose 3.3 V memory bus standard also sponsored by Hitachi and IBM (JESD8-8). This standard has two classes, I and II. SelectI/O devices support both classes for the SSTL3 standard. This standard requires a Differential Amplifier input buffer and an Push-Pull output buffer.

SSTL2 — Stub Series Terminated Logic for 2.5V

The Stub Series Terminated Logic for 2.5 V, or SSTL2 standard is a general purpose 2.5 V memory bus standard sponsored by Hitachi and IBM (JESD8-9). This standard has two classes, I and II. SelectI/O devices support both classes for the SSTL2 standard. This standard requires a Differential Amplifier input buffer and an Push-Pull output buffer.

CTT — Center Tap Terminated

The Center Tap Terminated, or CTT standard is a 3.3 V memory bus standard sponsored by Fujitsu (JESD8-4). This standard requires a Differential Amplifier input buffer and a Push-Pull output buffer.

AGP-2X — Advanced Graphics Port

The Intel AGP standard is a 3.3 V Advanced Graphics Port-2X bus standard used with the Pentium II processor for graphics applications. This standard requires a Push-Pull output buffer and a Differential Amplifier input buffer.

LVDS — Low Voltage Differential Signal

LVDS is a differential I/O standard. It requires that one data bit is carried through two signal lines. As with all differential signaling standards, LVDS has an inherent noise immunity over single-ended I/O standards. The voltage swing between two signal lines is approximately 350 mV. The use of a reference voltage (V_{REF}) or a board termination voltage (V_{TT}) is not required. LVDS requires the use of two pins per input or output. LVDS requires external resistor termination.

BLVDS — Bus LVDS

This standard allows for bidirectional LVDS communication between two or more devices. The external resistor termination is different than the one for standard LVDS.

LVPECL — Low Voltage Positive Emitter Coupled Logic

LVPECL is another differential I/O standard. It requires two signal lines for transmitting one data bit. This standard specifies two pins per input or output. The voltage swing between these two signal lines is approximately 850 mV. The use of a reference voltage (V_{REF}) or a board termination voltage (V_{TT}) is not required. The LVPECL standard requires external resistor termination.

Library Symbols

The Xilinx library includes an extensive list of symbols designed to provide support for the variety of SelectI/O features. Most of these symbols represent variations of the five generic SelectI/O symbols.

- IBUF (input buffer)
- IBUFG (global clock input buffer)
- OBUF (output buffer)
- OBUFT (3-state output buffer)
- IOBUF (input/output buffer)

IBUF

Signals used as inputs to the Virtex-E device must source an input buffer (IBUF) via an external input port. The generic Virtex-E IBUF symbol appears in Figure 37. The extension to the base name defines which I/O standard the IBUF uses. The assumed standard is LVTTL when the generic IBUF has no specified extension.

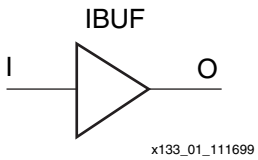

Figure 37: **Input Buffer (IBUF) Symbols**

The following list details the variations of the IBUF symbol:

- IBUF
- IBUF_LVCMOS2
- IBUF_PCI33_3
- IBUF_PCI66_3
- IBUF_GTL
- IBUF_GTLP
- IBUF_HSTL_I
- IBUF_HSTL_III
- IBUF_HSTL_IV
- IBUF_SSTL3_I
- IBUF_SSTL3_II
- IBUF_SSTL2_I
- IBUF_SSTL2_II
- IBUF_CTT
- IBUF_AGP
- IBUF_LVCMOS18
- IBUF_LVDS
- IBUF_LVPECL

When the IBUF symbol supports an I/O standard that requires a V_{REF}, the IBUF automatically configures as a differential amplifier input buffer. The V_{REF} voltage must be supplied on the V_{REF} pins. In the case of LVDS, LVPECL, and BLVDS, V_{REF} is not required.

The LVTTL OBUFT additionally can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL 3-state output buffers have selectable drive strengths.

The format for LVTTL OBUFT symbol names is as follows.

```
OBUFT_<slew_rate>_<drive_strength>
```

<slew_rate> can be either F (Fast), or S (Slow) and <drive_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24).

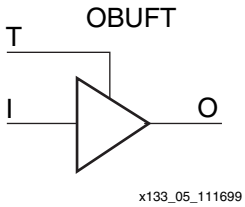

Figure 41: **3-State Output Buffer Symbol (OBUFT)**

The following list details variations of the OBUFT symbol.

- OBUFT
- OBUFT_S_2
- OBUFT_S_4
- OBUFT_S_6
- OBUFT_S_8
- OBUFT_S_12
- OBUFT_S_16
- OBUFT_S_24
- OBUFT_F_2
- OBUFT_F_4
- OBUFT_F_6
- OBUFT_F_8
- OBUFT_F_12
- OBUFT_F_16
- OBUFT_F_24
- OBUFT_LVCMOS2
- OBUFT_PCI33_3
- OBUFT_PCI66_3
- OBUFT_GTL
- OBUFT_GTLP
- OBUFT_HSTL_I
- OBUFT_HSTL_III
- OBUFT_HSTL_IV
- OBUFT_SSTL3_I
- OBUFT_SSTL3_II
- OBUFT_SSTL2_I
- OBUFT_SSTL2_II
- OBUFT_CTT
- OBUFT_AGP
- OBUFT_LVCMOS18
- OBUFT_LVDS
- OBUFT_LVPECL

The Virtex-E series supports eight banks for the HQ and PQ packages. The CS package supports four V_{CCO} banks.

The SelectI/O OBUFT placement restrictions require that within a given V_{CCO} bank each OBUFT share the same output source drive voltage. Input buffers of any type and output buffers that do not require V_{CCO} can be placed within the same V_{CCO} bank.

The LOC property can specify a location for the OBUFT.

3-state output buffers and bidirectional buffers can have either a weak pull-up resistor, a weak pull-down resistor, or a weak “keeper” circuit. Control this feature by adding the appropriate symbol to the output net of the OBUFT (PULLUP, PULLDOWN, or KEEPER).

The weak “keeper” circuit requires the input buffer within the IOB to sample the I/O signal. So, OBUFTs programmed for an I/O standard that requires a V_{REF} have automatic placement of a V_{REF} in the bank with an OBUFT configured with a weak “keeper” circuit. This restriction does not affect most circuit design as applications using an OBUFT configured with a weak “keeper” typically implement a bidirectional I/O. In this case the IBUF (and the corresponding V_{REF}) are explicitly placed.

The LOC property can specify a location for the OBUFT.

IOBUF

Use the IOBUF symbol for bidirectional signals that require both an input buffer and a 3-state output buffer with an active high 3-state pin. The generic input/output buffer IOBUF appears in Figure 42.

The extension to the base name defines which I/O standard the IOBUF uses. With no extension specified for the generic IOBUF symbol, the assumed standard is LVTTL input buffer and slew rate limited LVTTL with 12 mA drive strength for the output buffer.

The LVTTL IOBUF additionally can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL bidirectional buffers have selectable output drive strengths.

The format for LVTTL IOBUF symbol names is as follows.

```
IOBUF_<slew_rate>_<drive_strength>
```

<slew_rate> can be either F (Fast), or S (Slow) and <drive_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24).

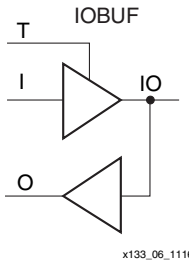

Figure 42: **Input/Output Buffer Symbol (IOBUF)**

The following list details variations of the IOBUF symbol.

- IOBUF
- IOBUF_S_2
- IOBUF_S_4
- IOBUF_S_6
- IOBUF_S_8
- IOBUF_S_12
- IOBUF_S_16
- IOBUF_S_24
- IOBUF_F_2
- IOBUF_F_4
- IOBUF_F_6
- IOBUF_F_8
- IOBUF_F_12
- IOBUF_F_16
- IOBUF_F_24
- IOBUF_LVCMOS2
- IOBUF_PCI33_3
- IOBUF_PCI66_3
- IOBUF_GTL
- IOBUF_GTLP
- IOBUF_HSTL_I
- IOBUF_HSTL_III
- IOBUF_HSTL_IV
- IOBUF_SSTL3_I
- IOBUF_SSTL3_II
- IOBUF_SSTL2_I
- IOBUF_SSTL2_II
- IOBUF_CTT
- IOBUF_AGP
- IOBUF_LVCMOS18
- IOBUF_LVDS
- IOBUF_LVPECL

When the IOBUF symbol used supports an I/O standard that requires a differential amplifier input, the IOBUF automatically configures with a differential amplifier input buffer. The low-voltage I/O standards with a differential amplifier input require an external reference voltage input V_{REF}.

The voltage reference signal is “banked” within the Virtex-E device on a half-edge basis such that for all packages there are eight independent V_{REF} banks internally. See Figure 38 on page 34 for a representation of the Virtex-E I/O banks. Within each bank approximately one of every six I/O pins is automatically configured as a V_{REF} input. After placing a differential amplifier input signal within a given V_{REF} bank, the same external source must drive all I/O pins configured as a V_{REF} input.

IOBUF placement restrictions require any differential amplifier input signals within a bank be of the same standard.

The Virtex-E series supports eight banks for the HQ and PQ packages. The CS package supports four V_{CCO} banks.

Additional restrictions on the Virtex-E SelectI/O IOBUF placement require that within a given V_{CCO} bank each IOBUF must share the same output source drive voltage. Input buffers of any type and output buffers that do not require V_{CCO} can be placed within the same V_{CCO} bank. The LOC property can specify a location for the IOBUF.

An optional delay element is associated with the input path in each IOBUF. When the IOBUF drives an input flip-flop within the IOB, the delay element activates by default to ensure a zero hold-time requirement. Override this default with the NODELAY=TRUE property.

In the case when the IOBUF does not drive an input flip-flop within the IOB, the delay element de-activates by default to provide higher performance. To delay the input signal, activate the delay element with the DELAY=TRUE property.

3-state output buffers and bidirectional buffers can have either a weak pull-up resistor, a weak pull-down resistor, or a weak “keeper” circuit. Control this feature by adding the appropriate symbol to the output net of the IOBUF (PULLUP, PULLDOWN, or KEEPER).

SelectI/O Properties

Access to some of the SelectI/O features (for example, location constraints, input delay, output drive strength, and slew rate) is available through properties associated with these features.

Input Delay Properties

An optional delay element is associated with each IBUF. When the IBUF drives a flip-flop within the IOB, the delay element activates by default to ensure a zero hold-time requirement. Use the NODELAY=TRUE property to override this default.

In the case when the IBUF does not drive a flip-flop within the IOB, the delay element by default de-activates to provide higher performance. To delay the input signal, activate the delay element with the DELAY=TRUE property.

Input termination techniques include the following:

- None
- Parallel (Shunt)

These termination techniques can be applied in any combination. A generic example of each combination of termination methods appears in Figure 43.

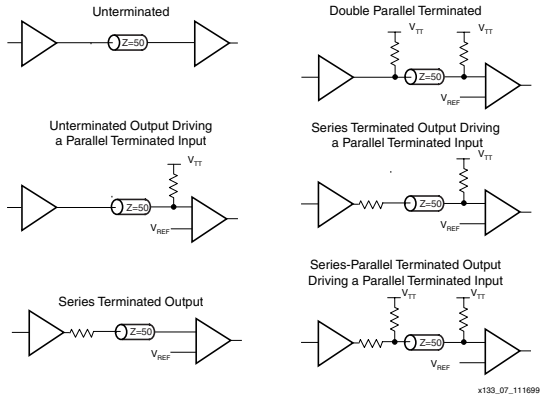

Figure 43: **Overview of Standard Input and Output Termination Methods**

Simultaneous Switching Guidelines

Ground bounce can occur with high-speed digital ICs when multiple outputs change states simultaneously, causing undesired transient behavior on an output, or in the internal logic. This problem is also referred to as the Simultaneous Switching Output (SSO) problem.

Ground bounce is primarily due to current changes in the combined inductance of ground pins, bond wires, and ground metallization. The IC internal ground level deviates from the external system ground level for a short duration (a few nanoseconds) after multiple outputs change state simultaneously.

Ground bounce affects stable Low outputs and all inputs because they interpret the incoming signal by comparing it to the internal ground. If the ground bounce amplitude exceeds the actual instantaneous noise margin, then a non-changing input can be interpreted as a short pulse with a polarity opposite to the ground bounce.

Table 21 provides the guidelines for the maximum number of simultaneously switching outputs allowed per output power/ground pair to avoid the effects of ground bounce. Refer to Table 22 for the number of effective output power/ground pairs for each Virtex-E device and package combination.

Table 21: **Guidelines for Maximum Number of Simultaneously Switching Outputs per Power/Ground Pair**

Standard	Package
	BGA, FGA
LVTTL Slow Slew Rate, 2 mA drive	68
LVTTL Slow Slew Rate, 4 mA drive	41
LVTTL Slow Slew Rate, 6 mA drive	29
LVTTL Slow Slew Rate, 8 mA drive	22
LVTTL Slow Slew Rate, 12 mA drive	17
LVTTL Slow Slew Rate, 16 mA drive	14
LVTTL Slow Slew Rate, 24 mA drive	9
LVTTL Fast Slew Rate, 2 mA drive	40
LVTTL Fast Slew Rate, 4 mA drive	24
LVTTL Fast Slew Rate, 6 mA drive	17
LVTTL Fast Slew Rate, 8 mA drive	13
LVTTL Fast Slew Rate, 12 mA drive	10
LVTTL Fast Slew Rate, 16 mA drive	8
LVTTL Fast Slew Rate, 24 mA drive	5
LVCMOS	10
PCI	8
GTL	4
GTL+	4
HSTL Class I	18
HSTL Class III	9
HSTL Class IV	5
SSTL2 Class I	15
SSTL2 Class II	10
SSTL3 Class I	11
SSTL3 Class II	7
CTT	14
AGP	9

Note: This analysis assumes a 35 pF load for each output.

Table 22: **Virtex-E Extended Memory Family Equivalent Power/Ground Pairs**

Pkg/Part	XCV405E	XCV812E
BG560		56
FG676	56	
FG900		

GCLKPAD3 can also be replaced with the package pin name, such as D17 for the BG432 package.

Creating LVDS Input Buffers

An LVDS input buffer can be placed in a wide number of IOB locations. The exact location is dependent on the package that is used. The Virtex-E package information lists the possible locations as IO_L#P for the P-side and IO_L#N for the N-side where # is the pair number.

HDL Instantiation

Only one input buffer is required to be instantiated in the design and placed on the correct IO_L#P location. The N-side of the buffer is reserved and no other IOB is allowed to be placed on this location. In the physical device, a configuration option is enabled that routes the pad wire from the IO_L#N IOB to the differential input buffer located in the IO_L#P IOB. The output of this buffer then drives the output of the IO_L#P cell or the input register in the IO_L#P IOB. In EPIC it appears that the second buffer is unused. Any attempt to use this location for another purpose leads to a DRC error in the software.

VHDL Instantiation

```
data0_p : IBUF_LVDS port map (I=>data(0),
O=>data_int(0));
```

Verilog Instantiation

```
IBUF_LVDS data0_p (.I(data[0]),
.O(data_int[0]));
```

Location Constraints

All LVDS buffers must be explicitly placed on a device. For the input buffers this can be done with the following constraint in the UCF or NCF file.

```
NET data<0> LOC = D28; # IO_L0P
```

Optional N-side

Some designers might prefer to also instantiate the N-side buffer for the input buffer. This allows the top-level net list to include net connections for both PCB layout and system-level integration. In this case, only the output P-side IBUF connection has a net connected to it. Since the N-side IBUF does not have a connection in the EDIF net list, it is trimmed from the design in MAP.

VHDL Instantiation

```
data0_p : IBUF_LVDS port map
(I=>data_p(0), O=>data_int(0));
data0_n : IBUF_LVDS port map
(I=>data_n(0), O=>open);
```

Verilog Instantiation

```
IBUF_LVDS data0_p (.I(data_p[0]),
.O(data_int[0]));
IBUF_LVDS data0_n (.I(data_n[0]), .O());
```

Location Constraints

All LVDS buffers must be explicitly placed on a device. For the global clock input buffers this can be done with the following constraint in the UCF or NCF file.

```
NET data_p<0> LOC = D28; # IO_L0P
NET data_n<0> LOC = B29; # IO_L0N
```

Adding an Input Register

All LVDS buffers can have an input register in the IOB. The input register is in the P-side IOB only. All the normal IOB register options are available (FD, FDE, FDC, FDCE, FDP, FDPE, FDR, FDRE, FDS, FDSE, LD, LDE, LDC, LDCE, LDP, LDPE). The register elements can be inferred or explicitly instantiated in the HDL code.

The register elements can be packed in the IOB using the IOB property to TRUE on the register or by using “map -pr [i|o|b]”, where “i” is inputs only, “o” is outputs only, and “b” is both inputs and outputs.

To improve design coding times VHDL and Verilog synthesis macro libraries available to explicitly create these structures. The input library macros are listed in Table 42. The I and IB inputs to the macros are the external net connections.

Table 42: **Input Library Macros**

Name	Inputs	Outputs
IBUFDS_FD_LVDS	I, IB, C	Q
IBUFDS_FDE_LVDS	I, IB, CE, C	Q
IBUFDS_FDC_LVDS	I, IB, C, CLR	Q
IBUFDS_FDCE_LVDS	I, IB, CE, C, CLR	Q
IBUFDS_FDP_LVDS	I, IB, C, PRE	Q
IBUFDS_FDPE_LVDS	I, IB, CE, C, PRE	Q
IBUFDS_FDR_LVDS	I, IB, C, R	Q
IBUFDS_FDRE_LVDS	I, IB, CE, C, R	Q
IBUFDS_FDS_LVDS	I, IB, C, S	Q
IBUFDS_FDSE_LVDS	I, IB, CE, C, S	Q
IBUFDS_LD_LVDS	I, IB, G	Q
IBUFDS_LDE_LVDS	I, IB, GE, G	Q
IBUFDS_LDC_LVDS	I, IB, G, CLR	Q
IBUFDS_LDCE_LVDS	I, IB, GE, G, CLR	Q
IBUFDS_LDP_LVDS	I, IB, G, PRE	Q
IBUFDS_LDPE_LVDS	I, IB, GE, G, PRE	Q

Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V_{CCINT}	Internal Supply voltage relative to GND, T_J = 0 °C to +85°C	Commercial	1.8 – 5%	1.8 + 5%	V
	Internal Supply voltage relative to GND, T_J = –40°C to +100°C	Industrial	1.8 – 5%	1.8 + 5%	V
V_{CCO}	Supply voltage relative to GND, T_J = 0 °C to +85°C	Commercial	1.2	3.6	V
	Supply voltage relative to GND, T_J = –40°C to +100°C	Industrial	1.2	3.6	V
T_{IN}	Input signal transition time			250	ns

DC Characteristics Over Recommended Operating Conditions

Symbol	Description(1)		Device	Min	Max	Units
V_{DRINT}	Data Retention V_{CCINT} Voltage (below which configuration data might be lost)		All	1.5		V
V_{DRIO}	Data Retention V_{CCO} Voltage (below which configuration data might be lost)		All	1.2		V
I_{CCINTQ}	Quiescent V_{CCINT} supply current[1]		XCV405E		400	mA
			XCV812E		500	mA
I_{CCOQ}	Quiescent V_{CCO} supply current[1]		XCV405E		2	mA
			XCV812E		2	mA
I_L	Input or output leakage current		All	–10	+10	µA
C_{IN}	Input capacitance (sample tested)	BGA, PQ, HQ, packages	All		8	pF
I_{RPU}	Pad pull-up (when selected) @ V_{in} = 0 V, V_{CCO} = 3.3 V (sample tested)		All	Note 2	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ V_{in} = 3.6 V (sample tested)			Note 2	0.25	mA

Notes:
1. With no output current loads, no active input pull-up resistors, all I/O pins 3-stated and floating.
2. Internal pull-up and pull-down resistors guarantee valid logic levels at unconnected input pins. These pull-up and pull-down resistors do not guarantee valid logic levels when input pins are connected to other circuits.

Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device operation. The actual current consumed depends on the power-on ramp rate of the power supply. This is the time required to reach the nominal power supply voltage of the device[1] from 0 V. The fastest ramp rate is 0 V to nominal voltage in 2 ms and the slowest allowed ramp rate is 0 V to nominal voltage in 50 ms. For more details on power supply requirements, see XAPP158 on www.xilinx.com.

Product (Commercial Grade)	Description(2)	Current Requirement(3)
XCV50E - XCV600E	Minimum required current supply	500 mA
XCV812E - XCV2000E	Minimum required current supply	1 A
XCV2600E - XCV3200E	Minimum required current supply	1.2 A
Virtex-E Family, Industrial Grade	Minimum required current supply	2 A

Notes:
1. Ramp rate used for this specification is from 0 - 1.8 V DC. Peak current occurs on or near the internal power-on reset threshold and lasts for less than 3 ms.
2. Devices are guaranteed to initialize properly with the minimum current available from the power supply as noted above.
3. Larger currents might result if ramp rates are forced to be faster.

Clock Distribution Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-8	-7	-6	
GCLK IOB and Buffer						
Global Clock PAD to output.	T_{GPIO}	0.38	0.7	0.7	0.7	ns, max
Global Clock Buffer I input to O output	T_{GIO}	0.11	0.19	0.45	0.50	ns, max

I/O Standard Global Clock Input Adjustments

Description[1]	Symbol	Standard	Speed Grade				Units
			Min	-8	-7	-6	
Data Input Delay Adjustments							
Standard-specific global clock input delay adjustments	$T_{GPLVTTL}$	LVTTL	0.0	0.0	0.0	0.0	ns, max
	$T_{GPLVCMOS2}$	LVCMOS2	–0.02	0.0	0.0	0.0	ns, max
	$T_{GPLVCMOS18}$	LVCMOS2	0.12	0.20	0.20	0.20	ns, max
	T_{GLVDS}	LVDS	0.23	0.38	0.38	0.38	ns, max
	$T_{GLVPECL}$	LVPECL	0.23	0.38	0.38	0.38	ns, max
	$T_{GPPCI33\_3}$	PCI, 33 MHz, 3.3 V	–0.05	0.08	0.08	0.08	ns, max
	$T_{GPPCI66\_3}$	PCI, 66 MHz, 3.3 V	–0.05	–0.11	–0.11	–0.11	ns, max
	T_{GPGTL}	GTL	0.20	0.37	0.37	0.37	ns, max
	T_{GPGTLP}	GTL+	0.20	0.37	0.37	0.37	ns, max
	T_{GPHSTL}	HSTL	0.18	0.27	0.27	0.27	ns, max
	$T_{GPSSTL2}$	SSTL2	0.21	0.27	0.27	0.27	ns, max
	$T_{GPSSTL3}$	SSTL3	0.18	0.27	0.27	0.27	ns, max
	T_{GPCTT}	CTT	0.22	0.33	0.33	0.33	ns, max
	T_{GPAGP}	AGP	0.21	0.27	0.27	0.27	ns, max

Notes:
1. Input timing for GPLVTTL is measured at 1.4 V. For other I/O standards, see Table 3.

CLB Arithmetic Switching Characteristics

Setup times not listed explicitly can be approximated by decreasing the combinatorial delays by the setup time adjustment listed. Precise values are provided by the timing analyzer.

Description[1]	Symbol	Speed Grade				Units
		Min	-8	-7	-6	
Combinatorial Delays						
F operand inputs to X via XOR	T_{OPX}	0.32	0.68	0.8	0.8	ns, max
F operand input to XB output	T_{OPXB}	0.35	0.65	0.8	0.9	ns, max
F operand input to Y via XOR	T_{OPY}	0.59	1.07	1.4	1.5	ns, max
F operand input to YB output	T_{OPYB}	0.48	0.89	1.1	1.3	ns, max
F operand input to COUT output	T_{OPCYF}	0.37	0.71	0.9	1.0	ns, max
G operand inputs to Y via XOR	T_{OPGY}	0.34	0.72	0.8	0.9	ns, max
G operand input to YB output	T_{OPGYB}	0.47	0.78	1.2	1.3	ns, max
G operand input to COUT output	T_{OPCYG}	0.36	0.60	0.9	1.0	ns, max
BX initialization input to COUT	T_{BXCY}	0.19	0.36	0.51	0.57	ns, max
CIN input to X output via XOR	T_{CINX}	0.27	0.50	0.6	0.7	ns, max
CIN input to XB	T_{CINXB}	0.02	0.04	0.07	0.08	ns, max
CIN input to Y via XOR	T_{CINY}	0.26	0.45	0.7	0.7	ns, max
CIN input to YB	T_{CINYB}	0.16	0.28	0.38	0.43	ns, max
CIN input to COUT output	T_{BYP}	0.05	0.10	0.14	0.15	ns, max
Multiplier Operation						
F1/2 operand inputs to XB output via AND	T_{FANDXB}	0.10	0.30	0.35	0.39	ns, max
F1/2 operand inputs to YB output via AND	T_{FANDYB}	0.28	0.56	0.7	0.8	ns, max
F1/2 operand inputs to COUT output via AND	T_{FANDCY}	0.17	0.38	0.46	0.51	ns, max
G1/2 operand inputs to YB output via AND	T_{GANDYB}	0.20	0.46	0.55	0.7	ns, max
G1/2 operand inputs to COUT output via AND	T_{GANDCY}	0.09	0.28	0.30	0.34	ns, max
Setup and Hold Times before/after Clock CLK						
CIN input to FFX	T_{CCKX}/T_{CKCX}	0.47 / 0	1.0 / 0	1.2 / 0	1.3 / 0	ns, min
CIN input to FFY	T_{CCKY}/T_{CKCY}	0.49 / 0	0.92 / 0	1.2 / 0	1.3 / 0	ns, min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.

Block RAM Switching Characteristics

Description[1]	Symbol	Speed Grade				Units
		Min	-8	-7	-6	
Sequential Delays						
Clock CLK to DOUT output	T_{BCKO}	0.63	2.46	3.1	3.5	ns, max
Setup and Hold Times before Clock CLK						
ADDR inputs	T_{BACK}/T_{BCKA}	0.42 / 0	0.9 / 0	1.0 / 0	1.1 / 0	ns, min
DIN inputs	T_{BDCK}/T_{BCKD}	0.42 / 0	0.9 / 0	1.0 / 0	1.1 / 0	ns, min
EN input	T_{BECK}/T_{BCKE}	0.97 / 0	2.0 / 0	2.2 / 0	2.5 / 0	ns, min
RST input	T_{BRCK}/T_{BCKR}	0.9 / 0	1.8 / 0	2.1 / 0	2.3 / 0	ns, min
WEN input	T_{BWCK}/T_{BCKW}	0.86 / 0	1.7 / 0	2.0 / 0	2.2 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T_{BPWH}	0.6	1.2	1.35	1.5	ns, min
Minimum Pulse Width, Low	T_{BPWL}	0.6	1.2	1.35	1.5	ns, min
CLKA -> CLKB setup time for different ports	T_{BCCS}	1.2	2.4	2.7	3.0	ns, min

Notes:
1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.

TBUF Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-8	-7	-6	
Combinatorial Delays						
IN input to OUT output	T_{IO}	0.0	0.0	0.0	0 .0	ns, max
TRI input to OUT output high-impedance	T_{OFF}	0.05	0.092	0.10	0.11	ns, max
TRI input to valid data on OUT output	T_{ON}	0.05	0.092	0.10	0.11	ns, max

JTAG Test Access Port Switching Characteristics

Description	Symbol	Value	Units
TMS and TDI Setup times before TCK	T_{TAPTK}	4.0	ns, min
TMS and TDI Hold times after TCK	T_{TCKTAP}	2.0	ns, min
Output delay from clock TCK to output TDO	T_{TCKTDO}	11.0	ns, max
Maximum TCK clock frequency	F_{TCK}	33	MHz, max

Virtex-E Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Listed below are representative values for typical pin locations and normal clock loading. Values are expressed in nanoseconds unless otherwise noted.

Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, *with* DLL

Description[1]	Symbol	Device[3]	Speed Grade[2]				Units
			Min	-8	-7	-6	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, *with* DLL. For data *output* with different standards, adjust the delays with the values shown in "IOB Output Switching Characteristics Standard Adjustments" on page 8.	$T_{ICKOFDLL}$	XCV405E	1.0	3.1	3.1	3.1	ns
		XCV812E	1.0	3.1	3.1	3.1	ns

Notes:
1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 50% V_{CC} threshold with 35 pF external capacitive load. For other I/O standards and different loads, see Table 2 and Table 3.
3. DLL output jitter is already included in the timing calculation.

Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, *without* DLL

Description[1]	Symbol	Device	Speed Grade[2]				Units
			Min	-8	-7	-6	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, *without* DLL. For data *output* with different standards, adjust the delays with the values shown in "IOB Output Switching Characteristics Standard Adjustments" on page 8.	T_{ICKOF}	XCV405E	1.6	4.5	4.7	4.9	ns
		XCV812E	1.8	4.8	5.0	5.2	ns

Notes:
1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 50% V_{CC} threshold with 35 pF external capacitive load. For other I/O standards and different loads, see Table 2 and Table 3.

Table 1: **BG560 BGA — XCV405E and XCV812E**

Bank	Pin Description	Pin#
NA	VCCINT	B18
NA	VCCINT	B28
NA	VCCINT	C22
NA	VCCINT	C24
NA	VCCINT	E9
NA	VCCINT	E12
NA	VCCINT	F2
NA	VCCINT	H30
NA	VCCINT	J1
NA	VCCINT	K32
NA	VCCINT	M3
NA	VCCINT	N1
NA	VCCINT	N29
NA	VCCINT	N33
NA	VCCINT	U5
NA	VCCINT	U30
NA	VCCINT	Y2
NA	VCCINT	Y31
NA	VCCINT	AB2
NA	VCCINT	AB32
NA	VCCINT	AD2
NA	VCCINT	AD32
NA	VCCINT	AG3
NA	VCCINT	AG31
NA	VCCINT	AJ13
NA	VCCINT	AK8
NA	VCCINT	AK11
NA	VCCINT	AK17
NA	VCCINT	AK20
NA	VCCINT	AL14
NA	VCCINT	AL22
NA	VCCINT	AL27
NA	VCCINT	AN25
0	VCCO	A22
0	VCCO	A26
0	VCCO	A30

Table 1: **BG560 BGA — XCV405E and XCV812E**

Bank	Pin Description	Pin#
0	VCCO	B19
0	VCCO	B32
1	VCCO	A10
1	VCCO	A16
1	VCCO	B13
1	VCCO	C3
1	VCCO	E5
2	VCCO	B2
2	VCCO	D1
2	VCCO	H1
2	VCCO	M1
2	VCCO	R2
3	VCCO	V1
3	VCCO	AA2
3	VCCO	AD1
3	VCCO	AK1
3	VCCO	AL2
4	VCCO	AN4
4	VCCO	AN8
4	VCCO	AN12
4	VCCO	AM2
4	VCCO	AM15
5	VCCO	AL31
5	VCCO	AM21
5	VCCO	AN18
5	VCCO	AN24
5	VCCO	AN30
6	VCCO	W32
6	VCCO	AB33
6	VCCO	AF33
6	VCCO	AK33
6	VCCO	AM32
7	VCCO	C32
7	VCCO	D33
7	VCCO	K33
7	VCCO	N32
7	VCCO	T33

Table 3: **FG676 Fine-Pitch BGA — XCV405E**

Bank	Pin Description	Pin #
NA	NC	B26
NA	NC	B24
NA	NC	B21
NA	NC	B16
NA	NC	B11
NA	NC	B1
NA	NC	AF25
NA	NC	AF24
NA	NC	AF2
NA	NC	AE6
NA	NC	AE3
NA	NC	AE26
NA	NC	AE24
NA	NC	AE21
NA	NC	AE16
NA	NC	AE14
NA	NC	AE11
NA	NC	AE1
NA	NC	AD25
NA	NC	AD2
NA	NC	AD1
NA	NC	AA6
NA	NC	AA25
NA	NC	AA21
NA	NC	AA2
NA	NC	A3
NA	NC	A25
NA	NC	A2
NA	NC	A15
NA	VCCINT	G7
NA	VCCINT	G20
NA	VCCINT	H8
NA	VCCINT	H19
NA	VCCINT	J9

Table 3: **FG676 Fine-Pitch BGA — XCV405E**

Bank	Pin Description	Pin #
NA	VCCINT	J10
NA	VCCINT	J11
NA	VCCINT	J16
NA	VCCINT	J17
NA	VCCINT	J18
NA	VCCINT	K9
NA	VCCINT	K18
NA	VCCINT	L9
NA	VCCINT	L18
NA	VCCINT	T9
NA	VCCINT	T18
NA	VCCINT	U9
NA	VCCINT	U18
NA	VCCINT	V9
NA	VCCINT	V10
NA	VCCINT	V11
NA	VCCINT	V16
NA	VCCINT	V17
NA	VCCINT	V18
NA	VCCINT	Y7
NA	VCCINT	Y20
NA	VCCINT	W8
NA	VCCINT	W19
0	VCCO	J13
0	VCCO	J12
0	VCCO	H9
0	VCCO	H12
0	VCCO	H11
0	VCCO	H10
1	VCCO	J15
1	VCCO	J14
1	VCCO	H18
1	VCCO	H17
1	VCCO	H16

Table 5: **FG900 Fine-Pitch BGA Package — XCV812E**

Bank	Description	Pin
0	IO_L29N	D14
0	IO_L29P	B14
0	IO_L30N_YY	A14
0	IO_L30P_YY	J14
0	IO_VREF_L31N_YY	K14
0	IO_L31P_YY	J15
0	IO_LVDS_DLL_L34N	A15
1	GCk2	E15
1	IO	B18
1	IO	B21
1	IO	B28
1	IO	C23
1	IO	C26
1	IO	D20
1	IO	D23
1	IO_LVDS_DLL_L34P	E16
1	IO_L35N	B16
1	IO_L35P	F16
1	IO_L36N	A16
1	IO_L36P	H16
1	IO_L37N_YY	C16
1	IO_VREF_L37P_YY	K15
1	IO_L38N_YY	K16
1	IO_L38P_YY	G16
1	IO_L39N	A17
1	IO_L39P	E17
1	IO_L40N	F17
1	IO_L40P	C17
1	IO_L41N_YY	E18
1	IO_VREF_L41P_YY	A18
1	IO_L42N_YY	D18
1	IO_L42P_YY	A19
1	IO_L43N	B19

Table 5: **FG900 Fine-Pitch BGA Package — XCV812E**

Bank	Description	Pin
1	IO_L43P	G18
1	IO_L44N	D19
1	IO_L44P	H18
1	IO_L45N_YY	F18
1	IO_VREF_L45P_YY	F19
1	IO_L46N_YY	B20
1	IO_L46P_YY	K17
1	IO_L48N_Y	G19
1	IO_L48P_Y	C20
1	IO_L49N_Y	K18
1	IO_L49P_Y	E20
1	IO_L51N_YY	F20
1	IO_L51P_YY	A21
1	IO_L52N_YY	C21
1	IO_VREF_L52P_YY	A22
1	IO_L53N	H19
1	IO_L53P	B22
1	IO_L54N	E21
1	IO_L54P	D22
1	IO_L55N_YY	F21
1	IO_VREF_L55P_YY	C22
1	IO_L56N_YY	H20
1	IO_L56P_YY	E22
1	IO_L57N	G21
1	IO_L57P	A23
1	IO_L58N	A24
1	IO_L58P	K19
1	IO_L59N_YY	C24
1	IO_VREF_L59P_YY	B24
1	IO_L60N_YY	H21
1	IO_L60P_YY	G22
1	IO_L61N	E23
1	IO_L61P	C25
1	IO_L62N	D24

Table 5: **FG900 Fine-Pitch BGA Package — XCV812E**

Bank	Description	Pin
5	IO_VREF_5_L198N_YY	AF9
5	IO_L199P_YY	AH9
5	IO_L199N_YY	AK9
5	IO_L200P	AF8
5	IO_L200N	AB11
5	IO_L201P	AC11
5	IO_L201N	AG8
5	IO_L202P_YY	AK8
5	IO_VREF_5_L202N_YY	AF7
5	IO_L203P_YY	AG7
5	IO_L203N_YY	AK7
5	IO_L204P	AJ7
5	IO_L204N	AD10
5	IO_L205P	AH6
5	IO_L205N	AC10
5	IO_L206P_YY	AD9
5	IO_VREF_5_L206N_YY	AG6
5	IO_L207P_YY	AB10
5	IO_L207N_YY	AJ5
5	IO_L209P_Y	AC9
5	IO_L209N_Y	AJ4
5	IO_L210P_Y	AG5
5	IO_L210N_Y	AK4
6	IO	T6
6	IO	U1
6	IO	U6
6	IO	V7
6	IO	V8
6	IO	W10
6	IO	Y10
6	IO	AA2
6	IO	AA4
6	IO	AD1

Table 5: **FG900 Fine-Pitch BGA Package — XCV812E**

Bank	Description	Pin
6	IO	AD6
6	IO	AG2
6	IO_L212N_YY	AF3
6	IO_L212P_YY	AC6
6	IO_L214N_Y	AB9
6	IO_L214P_Y	AE4
6	IO_L215N	AE3
6	IO_L215P	AH1
6	IO_L217N	AG1
6	IO_L217P	AA10
6	IO_VREF_L218N_Y	AA9
6	IO_L218P_Y	AD4
6	IO_L219N_YY	AD5
6	IO_L219P_YY	AD2
6	IO_L220N	AD3
6	IO_L220P	AF2
6	IO_L221N	AA8
6	IO_L221P	AA7
6	IO_VREF_L222N_YY	AF1
6	IO_L222P_YY	Y9
6	IO_L223N_YY	AB6
6	IO_L223P_YY	AC4
6	IO_L224N_Y	AE1
6	IO_L224P_Y	W8
6	IO_L225N	Y8
6	IO_L225P	AB4
6	IO_VREF_L226N	AB3
6	IO_L226P	W9
6	IO_L228N	AB1
6	IO_L228P	V10
6	IO_VREF	AC1
6	IO_L230N	V11
6	IO_L230P	AA3
6	IO_L232N_Y	W7

Table 5: **FG900 Fine-Pitch BGA Package — XCV812E**

Bank	Description	Pin
6	IO_L232P_Y	AA6
6	IO_L233N	Y6
6	IO_L233P	Y4
6	IO_L235N	Y3
6	IO_L235P	Y2
6	IO_VREF_L236N_Y	Y5
6	IO_L236P_Y	W5
6	IO_L237N_YY	W4
6	IO_L237P_YY	W6
6	IO_L238N	V6
6	IO_L238P	W2
6	IO_L239N	U9
6	IO_L239P	V4
6	IO_VREF_L240N_YY	AB2
6	IO_L240P_YY	T8
6	IO_L241N_YY	U5
6	IO_L241P_YY	W1
6	IO_L242N_Y	Y1
6	IO_L242P_Y	T9
6	IO_L243N	T7
6	IO_L243P	U3
6	IO_VREF_L244N	T5
6	IO_L244P	V2
6	IO_L246N	T4
6	IO_L246P	U2
6	IO_L247N	T1
7	IO	D1
7	IO	E3
7	IO	J4
7	IO	J6
7	IO	K10
7	IO	L3
7	IO	M7

Table 5: **FG900 Fine-Pitch BGA Package — XCV812E**

Bank	Description	Pin
7	IO	N8
7	IO	R5
7	IO_L247P	R10
7	IO_L249N	R8
7	IO_L249P	R4
7	IO_L250N	R7
7	IO_L250P	R3
7	IO_L251N	P10
7	IO_VREF_L251P	P6
7	IO_L252N	P5
7	IO_L252P	P2
7	IO_L253N_Y	P7
7	IO_L253P_Y	P4
7	IO_L254N_YY	N4
7	IO_L254P_YY	R2
7	IO_L255N_YY	N7
7	IO_VREF_L255P_YY	P1
7	IO_L256N	M6
7	IO_L256P	N6
7	IO_L257N	N5
7	IO_L257P	N1
7	IO_L258N_YY	M4
7	IO_L258P_YY	M5
7	IO_L259N_Y	M2
7	IO_VREF_L259P_Y	M1
7	IO_L260N	L4
7	IO_L260P	L2
7	IO_L262N	L1
7	IO_L262P	M8
7	IO_L263N_Y	K2
7	IO_L263P_Y	M9
7	IO_L265N_YY	K5
7	IO_L265P_YY	K1
7	IO_L266N_YY	L6

Table 6: **FG900 Differential Pin Pair Summary — XCV812E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
113	3	U24	V29	√	VREF
114	3	W30	U22	-	-
115	3	U21	W29	-	-
116	3	V26	W27	√	-
117	3	W26	Y29	√	VREF
118	3	W25	Y30	-	-
120	3	AA30	W24	-	-
121	3	AA29	V20	√	-
123	3	Y26	AB30	√	D5
124	3	V21	AA28	√	VREF
125	3	Y25	AA27	-	-
126	3	W22	Y23	-	-
127	3	Y24	AB28	-	VREF
128	3	AC30	AA25	-	-
129	3	W21	AA24	√	-
130	3	AB26	AD30	√	-
131	3	Y22	AC27	√	VREF
132	3	AD28	AB25	-	-
133	3	AC26	AE30	-	-
134	3	AD27	AF30	√	-
135	3	AF29	AB24	√	VREF
136	3	AB23	AE28	-	-
138	3	AE26	AG29	-	-
139	3	AH30	AC24	√	-
141	3	AH29	AA22	√	INIT
142	4	AF27	AK28	√	-
144	4	AD23	AJ27	√	-
145	4	AB21	AF25	√	-
147	4	AA21	AG25	√	-
148	4	AJ26	AD22	√	VREF
149	4	AA20	AH25	-	-
150	4	AC21	AF24	-	-
151	4	AG24	AK26	√	-
152	4	AJ24	AF23	√	VREF
153	4	AE23	AB20	-	-
154	4	AC20	AG23	-	-
155	4	AF22	AE22	√	-

Table 6: **FG900 Differential Pin Pair Summary — XCV812E**

Pair	Bank	P Pin	N Pin	AO	Other Functions
156	4	AJ22	AG22	√	VREF
158	4	AA19	AF21	-	-
160	4	AG21	AK23	-	-
162	4	AE20	AJ21	√	-
163	4	AG20	AF20	√	-
165	4	AJ20	AE19	√	-
166	4	AK22	AH20	√	VREF
167	4	AG19	AB17	-	-
168	4	AJ19	AD17	-	-
169	4	AA16	AA17	√	-
170	4	AK21	AB16	√	VREF
171	4	AG18	AK20	-	-
172	4	AK19	AD16	-	-
173	4	AE16	AE17	√	-
174	4	AG17	AJ17	√	VREF
176	4	AG16	AK17	-	-
177	5	AF16	AH16	-	GCLK LVDS 1/0
179	5	AB15	AF15	-	-
180	5	AA15	AF14	√	VREF
181	5	AH15	AK15	√	-
182	5	AB14	AF13	-	-
183	5	AH14	AJ14	-	-
184	5	AE14	AG13	√	VREF
185	5	AK13	AD13	√	-
186	5	AE13	AF12	-	-
187	5	AC13	AA13	-	-
188	5	AA12	AJ12	√	VREF
189	5	AB12	AE11	√	-
191	5	AG11	AF11	√	-
192	5	AH11	AJ11	√	-
194	5	AD12	AK11	√	-
195	5	AJ10	AC12	√	VREF
196	5	AK10	AD11	-	-
197	5	AJ9	AE9	-	-
198	5	AH10	AF9	√	VREF
199	5	AH9	AK9	√	-
200	5	AF8	AB11	-	-

Virtex-E Extended Memory Device/Package Combinations and Maximum I/O

Virtex-E Extended Memory Series Maximum User I/O by Device/Package (Excluding Dedicated Clock Pins)		
Package	**XCV405E**	**XCV812E**
BG560	404	404
FG676	404	
FG900		556

Virtex-E Ordering Information

Virtex-II ordering information is shown in Figure 1

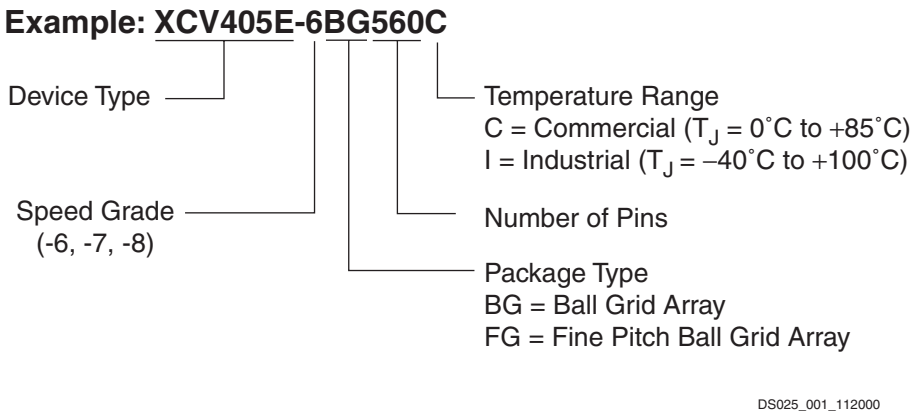

Figure 1: **Virtex Ordering Information**